

N-Channel 500V (D-S)Power MOSFET

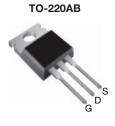
PRODUCT SUMMARY				
V _{DS} (V)	500			
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.660			
Q _g (Max.) (nC)	81			
Q _{gs} (nC)	20			
Q _{gd} (nC)	36			
Configuration	Single			

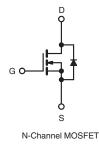
FEATURES

• Lower Gate Charge Q_g Results in Simpler Drive Regirements



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500	v	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	- I _D -	13		
	VGS at TO V	T _C = 100 °C		8.1	А	
Pulsed Drain Current ^a			I _{DM}	50		
Linear Derating Factor				2.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	560	mJ	
Avalanche Current ^a			I _{AR}	13	А	
Repetitive Avalanche Energy ^a			E _{AR}	25	mJ	
aximum Power Dissipation $T_{C} = 25 \text{ °C}$		P _D	250	W		
Peak Diode Recovery dV/dt ^c			dV/dt	9.2	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Taxous	6-32 or M3 screw			10	lbf ∙ in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 5.7 mH, R_g = 25 Ω , I_{AS} =14 A, dV/dt = 7.6 V/ns (see fig. 12a). c. I_{SD} ≤ 14 A, dI/dt ≤ 250 A/µs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greasd Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.50		

SPECIFICATIONS (T _J = 25 °C, u PARAMETER	SYMBOL		T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$		500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	Reference to 25 °C, $I_D = 1 \text{ mA}$		0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20V$	_	-	±100	nA
		$V_{DS} = 500 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	25	.
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 V	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.4 A ^b	-	0.660	-	Ω
Forward Transconductance	g fs	V _{DS}	= 50 V, I _D = 8.4 A	8.1	-	-	S
Dynamic		1			1		
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	1910	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$	-	290	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		11	-	
Output Capacitance	C _{oss}	V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz	-	2730	-	pF
			V _{DS} = 400 V, f = 1.0 MHz	-	82	-	
Effective Output Capacitance	C _{oss} eff.	$V_{DS} = 0 V \text{ to } 400 V^{c}$		-	160	-	1
Total Gate Charge	Qg			-	-	81	nC
Gate-Source Charge	Q _{gs}		I _D = 14 A, V _{DS} = 400 V, see fig. 6 and 13 ^b		-	20	
Gate-Drain Charge	Q_gd			-	-	36	1
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10 V		-	15	-	
Rise Time	t _r		V_{DD} = 250 V, I_D = 14 A, R_g = 7.5 Ω ,	ľ	39	-	- ns
Turn-Off Delay Time	t _{d(off)}		see fig. 10^{b}	I	39	-	
Fall Time	t _f				31	-	1
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol		-	13	A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	56	
Body Diode Voltage	V _{SD}	$T_J = 25 \ ^{\circ}C, \ I_S = 14 \ A, \ V_{GS} = 0 \ V^b$		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 14 A, T _J = 125 °C, dl/dt = 100 A/μs ^b		-	370	550	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	4.4	6.5	μC
Body Diode Reverse Recovery Current	I _{RRM}			-	21	31	Α
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

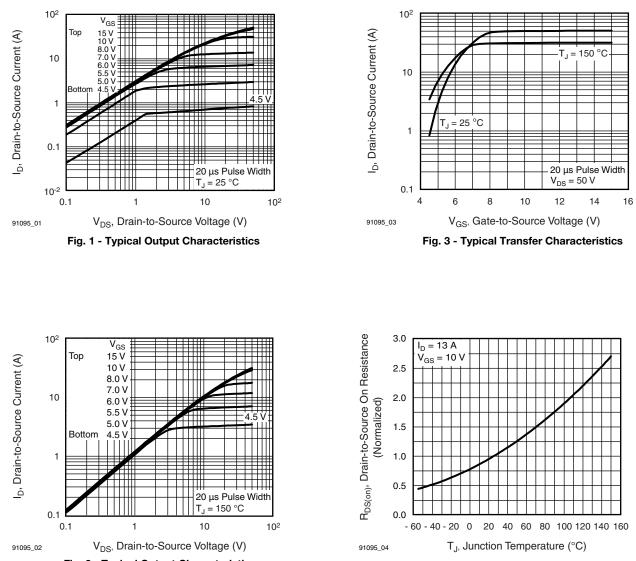
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.

c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







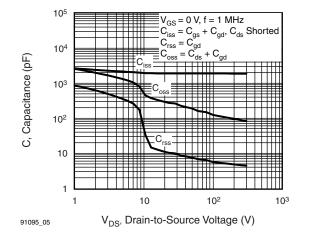


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

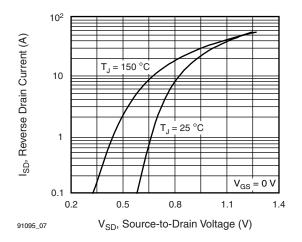


Fig. 7 - Typical Source-Drain Diode Forward Voltage

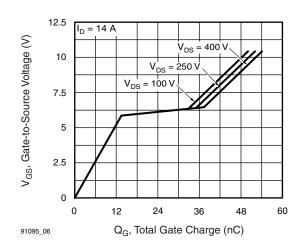


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

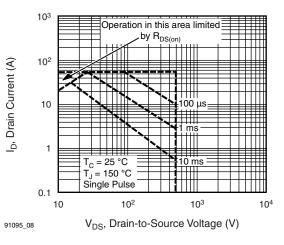


Fig. 8 - Maximum Safe Operating Area



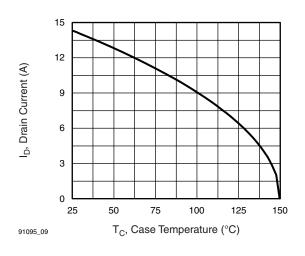


Fig. 9 - Maximum Drain Current vs. Case Temperature

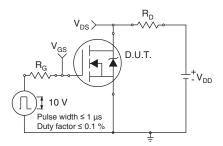


Fig. 10a - Switching Time Test Circuit

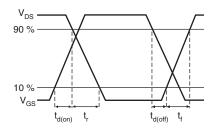


Fig. 10b - Switching Time Waveforms

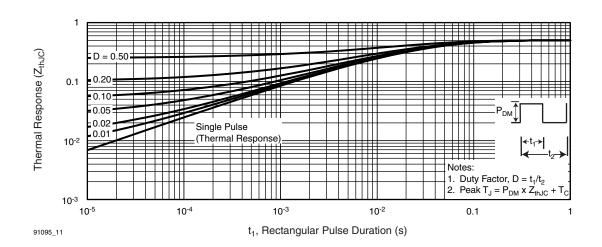


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



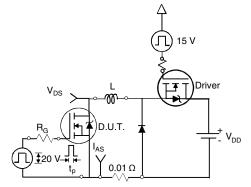


Fig. 12a - Unclamped Inductive Test Circuit

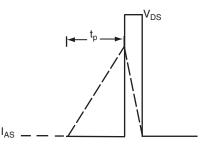


Fig. 12b - Unclamped Inductive Waveforms

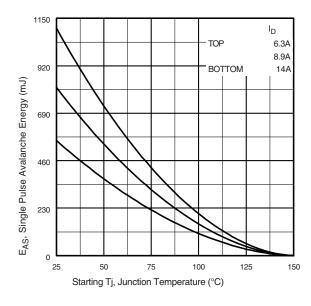


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

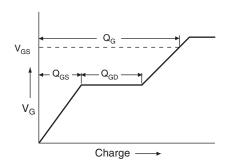


Fig. 13a - Basic Gate Charge Waveform

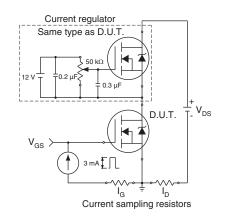
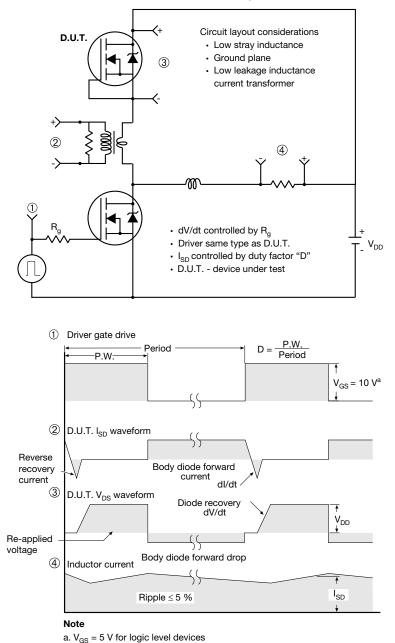


Fig. 13b - Gate Charge Test Circuit



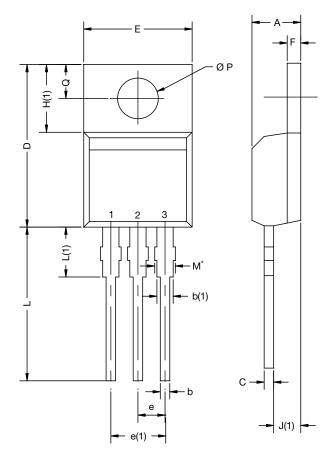


Peak Diode Recovery dV/dt Test Circuit

Fig. 14 - For N-Channel



TO-220AB



DIM	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
E	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031					

Note

- M^{\star} = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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